## Notice of References Cited

Application/Control No. 10/732,713	Reexaminati	Applicant(s)/Patent Under Reexamination NAIK, SANJEEV MANUBHAI		
Examiner	Art Unit	•		
Kiran B. Patel	3612	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,131,987	10-2000	Rossiter, Frank	296/97.2
*	В	US-5,472,255	12-1995	Moore, Thurman	296/97.6
*	С	US-4,874,938	10-1989	Chuang, Cliff	250/203.4
*	D	US-5,301,736	04-1994	Wu, Hans	296/97.8
*	Е	US-6,439,638	08-2002	Kawasaki et al.	296/97.2
*	F	US-6,089,643	07-2000	Wang et al.	296/97.2
*	G	US-5,954,386	09-1999	Thomas, James P.	296/97.2
*	Н	US-6,450,560	09-2002	Sturt et al.	296/97.2
*	ı	US-5,947,544	09-1999	Hubeshi, Carmel	296/97.8
*	J	US-5,042,866	08-1991	Cody, Ernest W.	296/97.4
*	к	US-5,873,621	02-1999	Kuighadush et al.	296/97.8
*	L	US-5,530,572	06-1996	He, Fan	250/201.1
*	М	US-6,056,424	05-2000	DiNunzio, Charles	362/490

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ŋ	JP11 34662	02-1999	JAPAN		
	0	DE3430824	03-1986	GERMANY		
	Р	JP 63 149242	06-1988	JAPAN		
	Q	JP 62 50222	03-1987	JAPAN		
	R	JP 55 148617	11-1980	JAPAN		
	s	JP672150	03-1994	JAPAN	· .	
	Т	JP63263132	10-1988	JAPAN		

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	٧				
	w				
	x				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.